

Notice of References Cited

Application/Control No.

09/868,239

Applicant(s)/Patent Under
Reexamination
ACKERMANN ET AL.

Examiner

Trang H. Cao

Art Unit

2857

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0013008	08-2001	WACLAWSKI, ANTHONY C.	705/10
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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